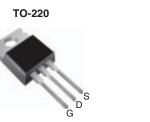
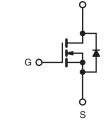


### **Power MOSFET**

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	600				
R <sub>DS(on)</sub> (Ω)	$V_{GS} = 10 V$	0.35			
Q <sub>g</sub> (Max.) (nC)	99				
Q <sub>gs</sub> (nC)	32				
Q <sub>gd</sub> (nC)	47				
Configuration	Single				





N-Channel MOSFET

#### FEATURES

- Smaller TO-220 Package
- Low Gate Charge Q<sub>g</sub> Results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Lead (Pb)-free Available

### **APPLICATIONS**

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply
- High Speed Power Switching
- · Hard Switched and High Frequency Circuits

ORDERING INFORMATION	
Package	TO-220
Lead (Pb)-free	IRFB17N60KPbF
	SiHFB17N60K-E3
SnPb	IRFB17N60K
	SiHFB17N60K

ABSOLUTE MAXIMUM RATINGS T	<sub>C</sub> = 25 °C, u	nless otherw	vise noted			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	600	- V	
Gate-Source Voltage			V <sub>GS</sub>	± 30		
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C		17		
		$T_C = 100 ^{\circ}C$	I <sub>D</sub>	11	А	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	68	1	
Linear Derating Factor				2.7	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	330	mJ	
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	17	А	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub> 34		mJ	
Maximum Power Dissipation	T <sub>C</sub> = 25 °C		PD	340	W	
Peak Diode Recovery dV/dtc			dV/dt	11	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	•••	
Soldering Recommendations (Peak Temperature)	for 10 s			300 <sup>d</sup>	- °C	
Mounting Torque	6-32 or I	M3 screw		10	N	

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Starting  $T_J = 25$  °C, L = 2.3 mH,  $R_G = 25 \Omega$ ,  $I_{AS} = 17 A$  (see fig. 12).

c.  $I_{SD} \leq 17$  A, dI/dt  $\leq 380$  A/µs,  $V_{DD} \leq V_{DS}$ ,  $T_J \leq 150$  °C.

d. 1.6 mm from case.

\* Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RAT	TINGS						
PARAMETER	SYMBOL	TYP. MAX.			UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	- 58			°C/W		
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>	0.50 -					
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	- 0.37					
	•	•					
<b>SPECIFICATIONS</b> $T_J = 25 \ ^{\circ}C$ ,	unless otherv	vise noted					
PARAMETER	SYMBOL	TES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static				•			
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub>	= 0 V, I <sub>D</sub> = 250 μA	600	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referen	ce to 25 °C, $I_D = 1 \text{ mA}$	-	600	-	mV/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> :	3.0	-	5.0	V	
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 30 V			± 100	nA
		$V_{DS} = 600 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		-	-	50	1
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> = 480 V	/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	250	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 10 A <sup>b</sup>	-	0.35	0.42	Ω
Forward Transconductance	<b>g</b> fs	V <sub>DS</sub>	= 50 V, I <sub>D</sub> = 10 A	5.9	-	-	S
Dynamic				•			1
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V,		-	2700	-	
Output Capacitance	C <sub>oss</sub>		V <sub>DS</sub> = 25 V,	-	240	-	-
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0 MHz, see fig. 5		-	21	-	pF
	C <sub>oss</sub>	V <sub>GS</sub> = 0 V	-	2950	-		
Output Capacitance		V <sub>GS</sub> = 0 V	$V_{DS} = 1.0 \text{ V}$ , f = 1.0 MHz $V_{DS} = 480 \text{ V}$ , f = 1.0 MHz	-	67	-	1
Effective Output Capacitance	C <sub>oss</sub> eff.	V <sub>GS</sub> = 0 V	V <sub>DS</sub> = 0 V to 480 V	-	120	-	
Total Gate Charge	Qg			-	-	99	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 17 A, V <sub>DS</sub> = 480 V	-	-	32	nC
Gate-Drain Charge	Q <sub>gd</sub>		see fig. 6 and 13	-	-	47	
Turn-On Delay Time	t <sub>d(on)</sub>			-	25	-	
Rise Time	t <sub>r</sub>	$V_{DD}=300~V,~I_{D}=17~A,$ $R_{G}=7.5~\Omega,~V_{GS}=10~V,~see~fig.~10^{b}$		_	82	-	- ns
Turn-Off Delay Time	t <sub>d(off)</sub>			_	38	-	
Fall Time	t <sub>f</sub>			-	32	-	
Drain-Source Body Diode Characteristic				•	-		
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET sym	bol	-	-	17	
	.0	showing the integral reverse p - n junction diode					A
Pulsed Diode Forward Currenta	I <sub>SM</sub>			-	-	68	
Body Diode Voltage	V <sub>SD</sub>	$T_{J} = 25 \text{ °C}, I_{S} = 17 \text{ A}, V_{GS} = 0 \text{ V}^{b}$		-	-	1.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_{\rm J} = 25 \ ^{\circ}\text{C}, \ \text{I}_{\text{F}} = 17 \ \text{A}, \ \text{dl/dt} = 100 \ \text{A/}\mu\text{s}^{\text{b}}$		-	520	780	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	5620	8430	nC
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_{J} = 125 \ ^{\circ}C, I_{F} = 17 \ A, \ dI/dt = 100 \ A/\mu s^{b}$		-	580	870	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	6470	9700	nC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic tu	Irn-on time is negligible (turn	-on is dor	ninated by		5

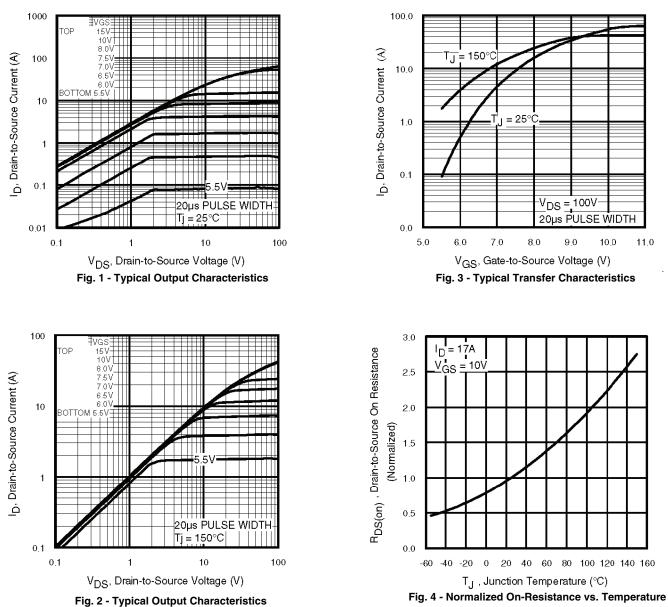
#### Notes

a. Repetitive rating, pulse width limited by max. junction temperature. b. Pulse width  $\leq$  300  $\mu s;$  duty cycle  $\leq$  2 %.



### IRFB17N60K, SiHFB17N60K

**Vishay Siliconix** 



### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

# IRFB17N60K, SiHFB17N60K

### Vishay Siliconix

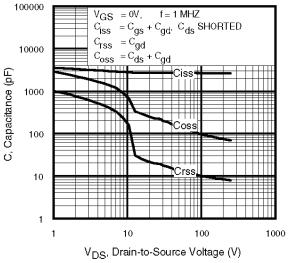


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

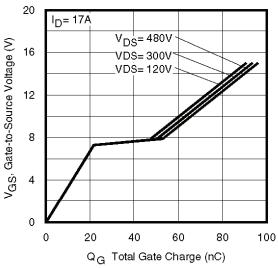


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

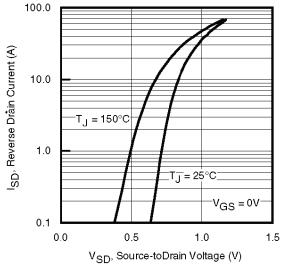
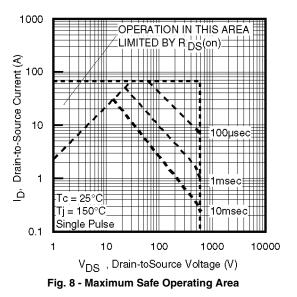


Fig. 7 - Typical Source-Drain Diode Forward Voltage

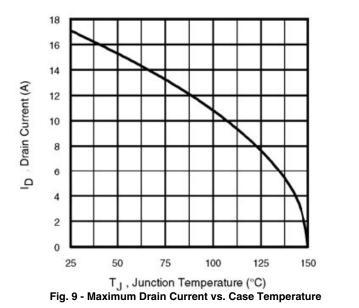


VISHAY.



### IRFB17N60K, SiHFB17N60K

### **Vishay Siliconix**



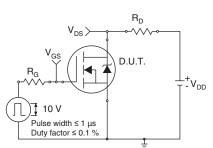


Fig. 10a - Switching Time Test Circuit

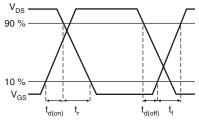
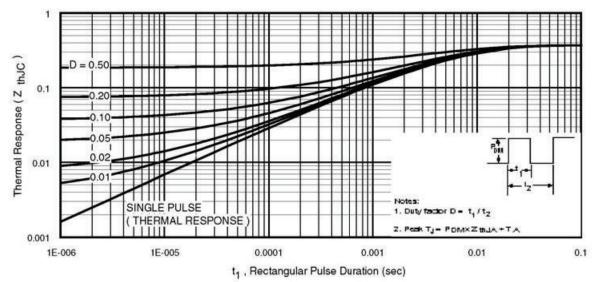
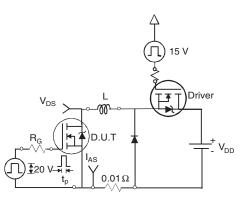
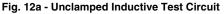


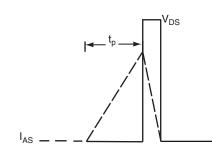
Fig. 10b - Switching Time Waveforms

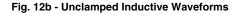














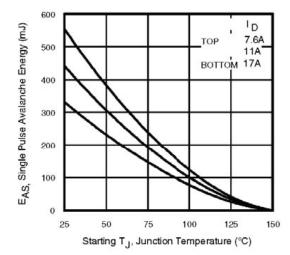


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

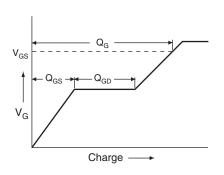


Fig. 13a - Basic Gate Charge Waveform

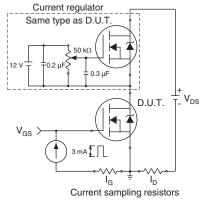
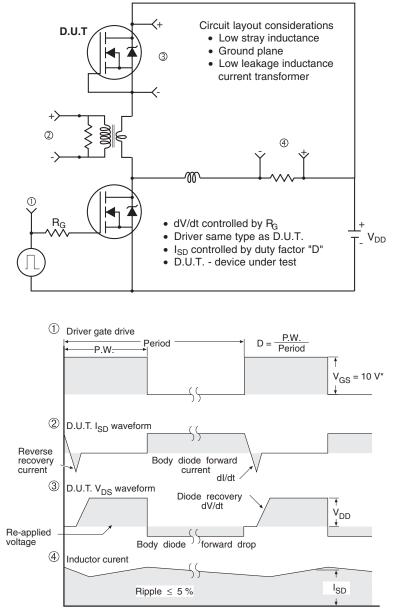


Fig. 13b - Gate Charge Test Circuit





Peak Diode Recovery dV/dt Test Circuit

\*  $V_{GS} = 5 V$  for logic level devices

Fig. 14 - For N-Channel

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